

Phosphoric Acid, 85%
CMOS

(orthophosphoric acid)



Material No.: 0264-05
Batch No.: 0000091038
Manufactured Date: 2014/09/17
Retest Date: 2019/09/16

Certificate of Analysis

Test	Specification	Result
Assay (H ₃ PO ₄) (by acidimetry)	85.0 – 87.0 %	86.2
Color (APHA)	<= 10	6
Color after Heating	Passes Test	PT
Specific Gravity at 60°/60°F	1.691 – 1.710	1.697
Reducing Substances	Passes Test	PT
Volatile Acids (µeq/g)	<= 0.16	< 0.16
Chloride (Cl)	<= 1 ppm	< 1
Nitrate (NO ₃)	<= 2 ppm	< 2
Sulfate (SO ₄)	<= 12 ppm	< 4
Trace Impurities – Aluminum (Al)	<= 0.500 ppm	< 0.020
Trace Impurities – Antimony (Sb)	<= 10.000 ppm	< 0.300
Trace Impurities – Arsenic (As)	<= 0.050 ppm	< 0.030
Trace Impurities – Calcium (Ca)	<= 1.500 ppm	0.021
Trace Impurities – Chromium (Cr)	<= 0.200 ppm	0.129
Trace Impurities – Cobalt (Co)	<= 0.050 ppm	< 0.010
Trace Impurities – Copper (Cu)	<= 0.050 ppm	0.014
Trace Impurities – Gold (Au)	<= 0.300 ppm	0.030
Trace Impurities – ACS – Heavy Metals (as Pb)	<= 5 ppm	< 3
Trace Impurities – Iron (Fe)	<= 2.000 ppm	< 0.100
Trace Impurities – Lead (Pb)	<= 0.300 ppm	0.040
Trace Impurities – Lithium (Li)	<= 0.100 ppm	< 0.001
Trace Impurities – Magnesium (Mg)	<= 0.2 ppm	< 0.001
Trace Impurities – Manganese (Mn)	<= 0.100 ppm	0.033
Trace Impurities – Nickel (Ni)	<= 0.200 ppm	0.021

Test	Specification	Result
Trace Impurities – Potassium (K)	<= 1.500 ppm	0.020
Trace Impurities – Sodium (Na)	<= 2.500 ppm	< 0.020
Trace Impurities – Strontium (Sr)	<= 0.100 ppm	< 0.005
Trace Impurities – Titanium (Ti)	<= 0.300 ppm	< 0.030
Trace Impurities – Zinc (Zn)	<= 2.000 ppm	< 0.040
Particle Count – 1.0 µm and greater	<= 10 par/ml	7

For Microelectronic Use

For additional information, go to www.askavantor.com. Search keywords
"freezing" and product name.

Storage Conditions: Store at temperatures above 22°C (72°F)

Country of Origin: US

Packaging Site: Paris Mfg Ctr & DC



Phillipsburg, NJ 9001:2008, 14001:2004
Paris, KY 9001:2008
Mexico City, Mexico 9001:2008
Deventer, The Netherlands 9001:2008, 14001:2004, 13485:2003
Gliwice, Poland 9001:2008, 17025:2005
Selangor, Malaysia 9001:2008
Dehradun, India, 9001:2008, 14001:2004, 13485:2003
Mumbai, India, 9001:2008, 17025:2005
Panoli, India 9001:2008

A handwritten signature in white ink on a blue background, reading "Richard M Siberski".

Richard M Siberski
Vice President Global Quality

For questions on this Certificate of Analysis please contact Technical Services at 855.282.6867 or +1.610.573.2600
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